

ABSTRACT OF THE DISCLOSURE

An input/output pin for test corresponding to a test circuit of the digital section is used in common as the input/output pin for usual operation of the analog section, the selection switches are respectively provided between the relevant analog pin and analog circuit and on a signal line up to the test circuit of the digital section from the relevant analog pin and the switches are provided at both end portions of the signal line between the test circuit of digital section and the input/output pin for common use in order to fix the voltage of the signal line to the predetermined voltage such as the ground voltage during the usual operation. Thereby, it is possible in a semiconductor integrated circuit comprising the analog and digital sections to eliminate adverse effect, even if the input/output pin for test corresponding to the test circuit of the digital section is used in common as the input/output pin for usual operation of the analog section, from the analog circuit due to the noise which is generated in the digital section and is then transferred to the analog circuit through the signal path up to the analog input/output pin connected to the test circuit from this test circuit of the digital section.